



Active

- ☒ L1: (0) ("flash adj memory
- ☒ L2: (17671) flash adj memo
- ☒ L3: (2645) flash adj memor
- ☒ L4: (2) 3 and (gate adj li
- ☒ L5: (18) 3 and (gate and g

☐ Failed

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DBs USPAT:EPD:JPD

☒ Plurals

Default operator: OR

☒ Highlight all hit terms initial

3 and (gate and gate adj insulating and metal adj silicide)

BRS I... IS&R... Image Text HTML

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef
1	<input type="checkbox"/>	<input type="checkbox"/>	US 6531360 B2	20030311	19	Method of manufacturing a flash memory device	438/257	438/264; 438/266
2	<input type="checkbox"/>	<input type="checkbox"/>	US 6521941 B2	20030218	15	Non-volatile memory device and fabrication method	257/315	257/314
3	<input type="checkbox"/>	<input type="checkbox"/>	US 6493271 B2	20021210	92	Data line disturbance free memory block divided flash	365/185.33	365/185.22; 365/185.28;
4	<input type="checkbox"/>	<input type="checkbox"/>	US 6475857 B1	20021105	20	Method of making a scalable two transistor memory device	438/240	438/258
5	<input type="checkbox"/>	<input type="checkbox"/>	US 6448112 B2	20020910	21	Cell array region of a NOR-type mask ROM device and	438/128	257/E21.673; 438/275;
6	<input type="checkbox"/>	<input type="checkbox"/>	US 6414878 B2	20020702	91	Data line disturbance free memory block divided flash	365/185.33	365/185.11
7	<input type="checkbox"/>	<input type="checkbox"/>	US 6400609 B1	20020604	92	Data line disturbance free memory block divided flash	365/185.28	365/185.11; 365/185.29
8	<input type="checkbox"/>	<input type="checkbox"/>	US 6376876 B1	20020423	21	NAND-type flash memory devices and methods of	257/315	257/319
9	<input type="checkbox"/>	<input type="checkbox"/>	US 6335879 B1	20020101	93	Method of erasing and programming a flash memory	365/185.08	365/185.28; 365/185.29
10	<input type="checkbox"/>	<input type="checkbox"/>	US 6181598 B1	20010130	95	Data line disturbance free memory block divided flash	365/185.11	257/315; 365/185.33
11	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6166953 A	20001226	93	Data line disturbance free memory block divided flash	365/185.11	365/185.28; 365/185.29;